Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	2	(US-6188582-$ or US-6260998-$).did.	USPAT	OR	OFF	2005/03/20 15:03
L4	692	703/13.ccls.	US-PGPUB; USPAT; USOCR	ADJ	OFF	2005/03/20 15:04
L5	546	703/22.ccls.	US-PGPUB; USPAT; USOCR	ADJ	OFF	2005/03/20 15:04
S2	787	mean time between failure	US-PGPUB; USPAT; USOCR	ADJ	OFF	2005/03/15 15:09
S3	323	S2 and (semiconductor or (integrated adj circuit) or ASIC)	US-PGPUB; USPAT; USOCR	ADJ	OFF	2005/03/15 15:10
S4	38	coffin adj manson	US-PGPUB; USPAT; USOCR	ADJ	OFF	2005/03/20 15:04
S5	17	hot cold testing	US-PGPUB; USPAT; USOCR	ADJ	OFF	2005/03/15 17:10
S7	691	(reliability test$3) with (semiconductor or ASIC or IC)	US-PGPUB; USPAT; USOCR	ADJ	OFF	2005/03/15 17:12
S9	1228	MTBF	US-PGPUB; USPAT; USOCR	ADJ	OFF	2005/03/15 17:15
S10	757	S9 and (semiconductor$3 or ASIC or package or chip or IC or silicon)	US-PGPUB; USPAT; USOCR	ADJ	OFF	2005/03/15 17:15
S11	33	MTBF with (semiconductor$3 or ASIC or package or chip or IC or silicon)	US-PGPUB; USPAT; USOCR	ADJ	OFF	2005/03/15 17:18
S12	0	(thermal adj profil$3) same (warrenty) same (MTBF)	US-PGPUB; USPAT; USOCR	ADJ	OFF	2005/03/15 17:19
S13	0	(thermal adj profil$3) same (warrenty)	US-PGPUB; USPAT; USOCR	ADJ	OFF	2005/03/16 12:57
S14	0	"09982061"	US-PGPUB; USPAT; USOCR	ADJ	OFF	2005/03/16 12:57
S15	1	"09/982061"	US-PGPUB; USPAT; USOCR	ADJ	OFF	2005/03/16 12:57